



IEC TS 62804-1:2015

Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced degradation

Part 1: Crystalline silicone
Confirmation of test results

Ref.: 10036/2021-40045

Applicant: LG Electronics Inc.
168, Suchul-daero, Gumi-si, Gyeongsangbuk-do,
730-903, South Korea

Product: Crystalline Silicon Photovoltaic (PV)-Modules

Type: A) LGXXXQ1K-N5
B) LGXXXQ1C-N5
C) LGXXXQ1C-A6
D) LGXXXQ1K-A6
E) LGXXXQAC-A6
F) LGXXXQAK-A6

XXX in the type replace the power in Watt and can be any number between: 360-390 for A), B), 375-405 for C), D) and 415-445 for E), F).

Manufacturer: LG Electronics Inc.

Standard: IEC TS 62804-1:2015

Test conditions:

Testing time: 96 h

Chamber temperature: 85°C

Relative Humidity: 85 %

Potential to ground: +/- 1000 V

Pass criteria:

Power degradation: <3%

Wet insulation resistance: >40 MΩ

Visual Inspection: No findings



Summary of test results:

Maximum power degradation:	allowed	max. 3 %
	measured	max. 0.85 %

The measured degradation is below the allowed degradation.

Wet insulation resistance:	required	min. 23.1 MΩ
	measured	>999 MΩ

The measured wet insulation resistance is above the limit.

Visual inspection: No findings

The complete test results and the relevant bill of materials are given in Test Report No.: TRPVM-2021-40045-2.

VDE Renewables GmbH


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